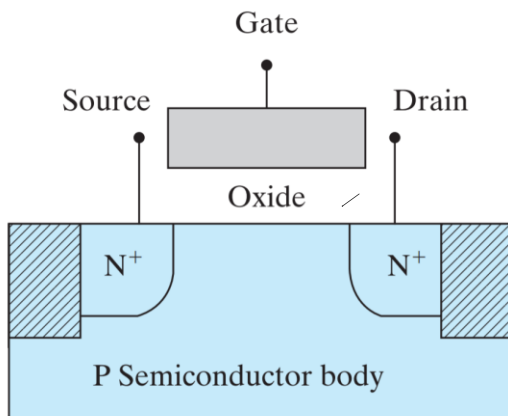


# MS Contacts and Schottky diodes



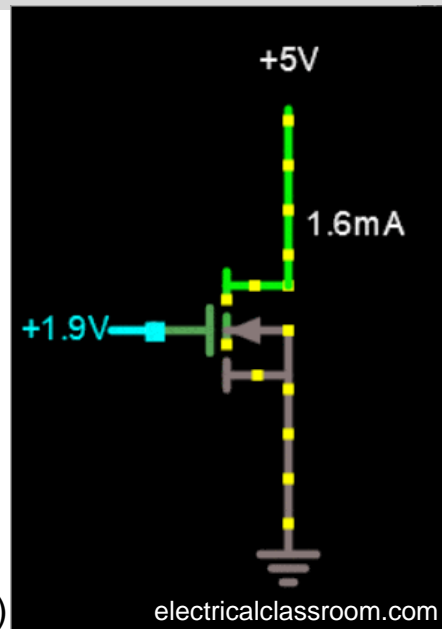
EE302

Prof. Sangyoon Han

Fall 2023

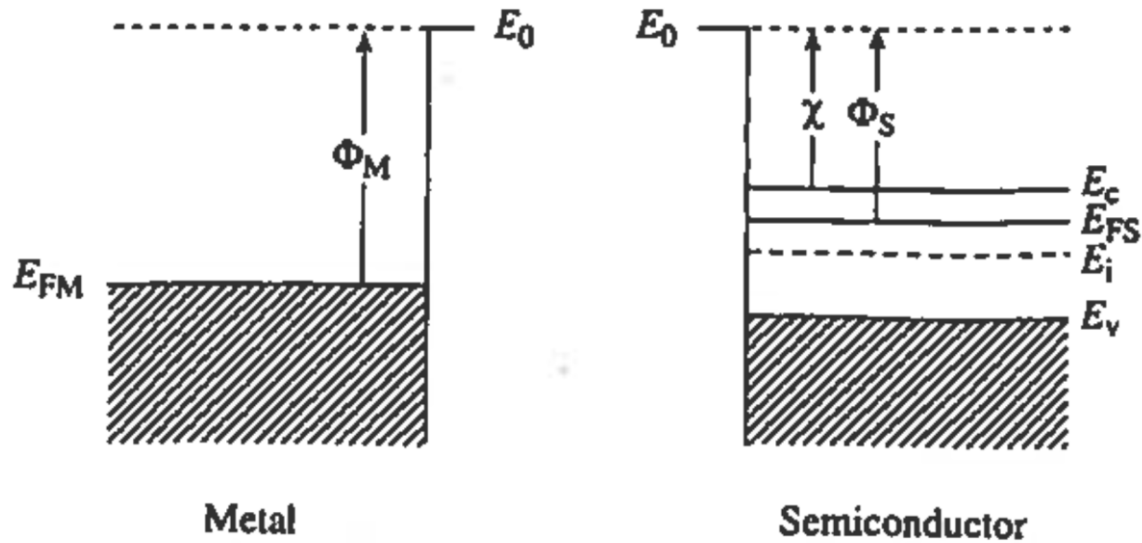
## References:

- (R. Pierret) Chapter 14
- (C. Hu) Chapter 4
- Materials from SE393 (Prof. Hongki Kang)



- **Metal–Semiconductor contacts**
  - What would happen if metal meets semiconductor?
  
- **Schottky Diodes**
  - Similar to PN diode
  - Metal / Semiconductor

# Ideal MS Contacts

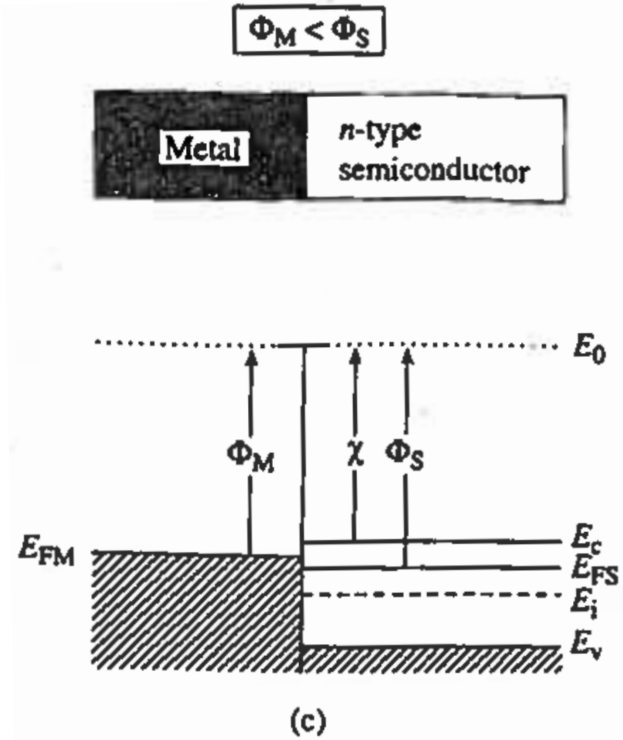
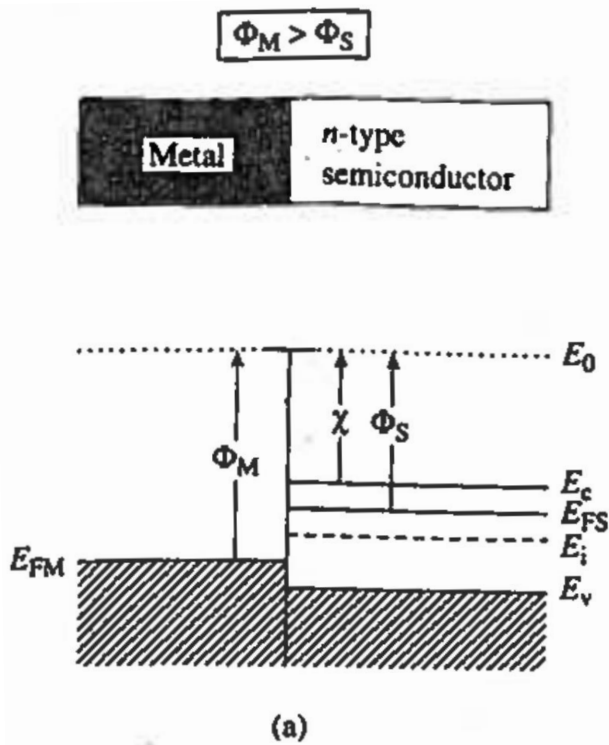


- $E_0$ : Vacuum level
- $E_{F(M,S)}$ : Fermi level
- $\chi$ : Electron affinity
  - $\chi = E_0 - E_c$
- $\phi_{(M,S)}$ : Workfunction
  - $\phi_M = E_0 - E_{FM}, \phi_S = E_0 - E_{FS}$

**Table 14.1** Electrical Nature of Ideal MS Contacts.

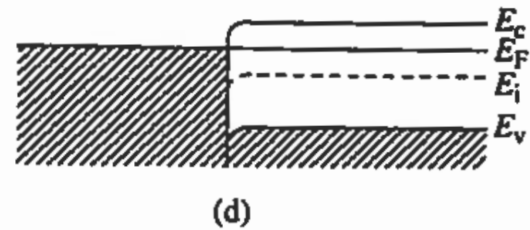
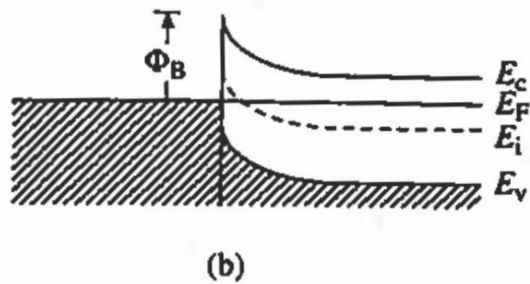
	<i>n-type Semiconductor</i>	<i>p-type Semiconductor</i>
$\Phi_M > \Phi_S$	Rectifying	Ohmic
$\Phi_M < \Phi_S$	Ohmic	Rectifying

# Metal / *n*-type Semiconductor



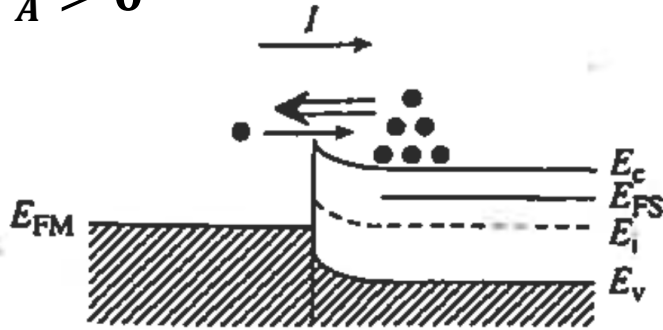
Surface potential energy barrier

$$\phi_B = \phi_M - \chi$$

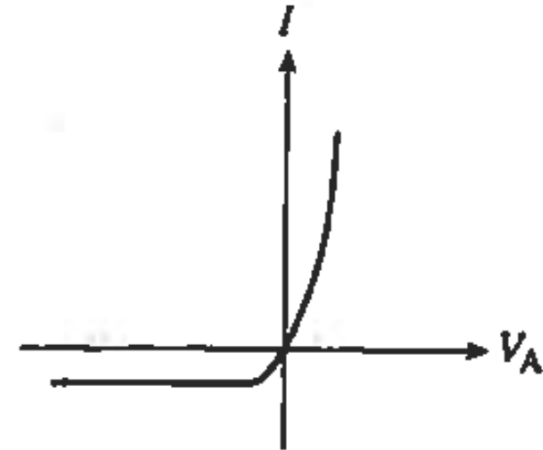
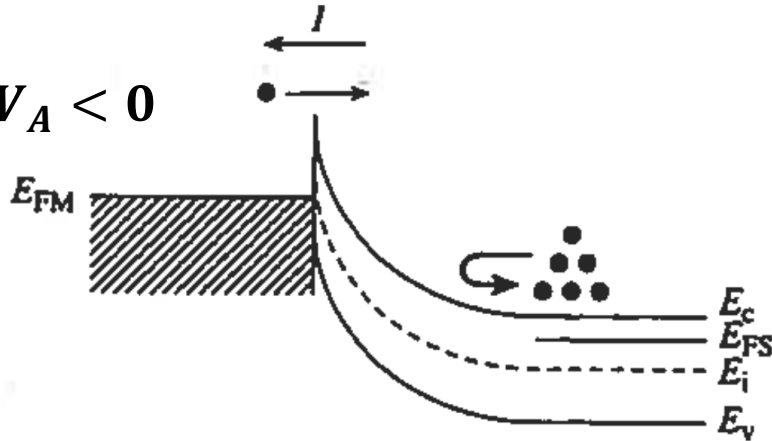


# Metal / *n*-type Semiconductor ( $\phi_M > \phi_S$ , rectifying contact)

- $V_A > 0$

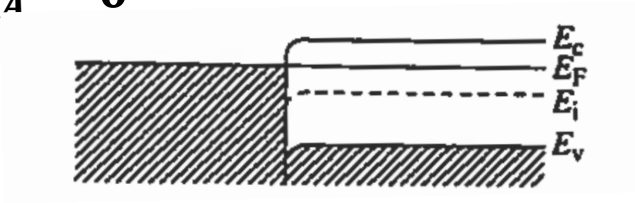


- $V_A < 0$

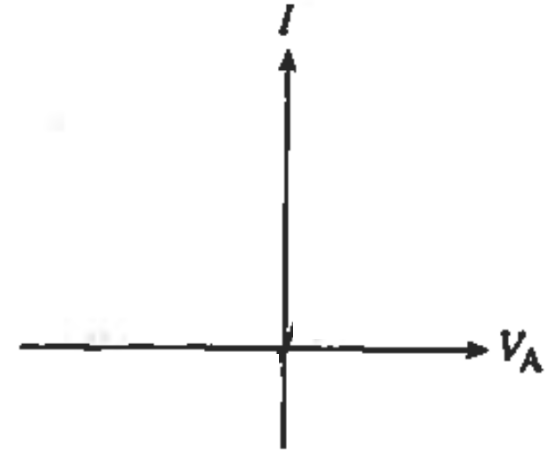


# Metal / *n*-type Semiconductor ( $\phi_M < \phi_S$ , *ohmic contact*)

- $V_A = 0$

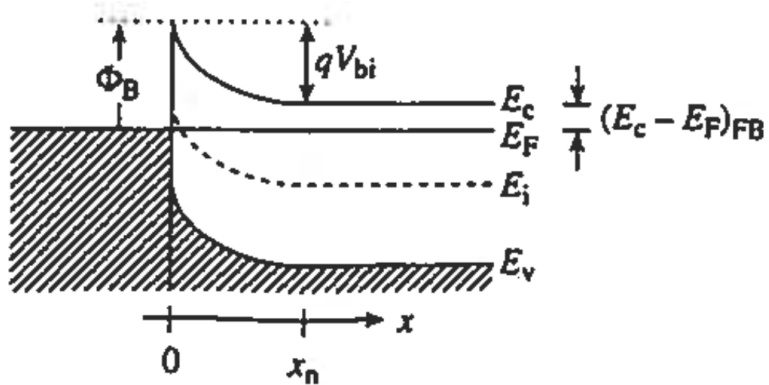


- $V_A > 0$

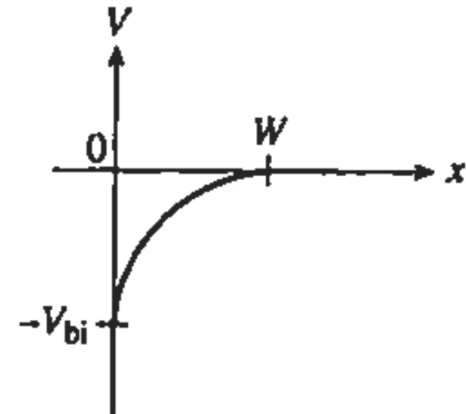
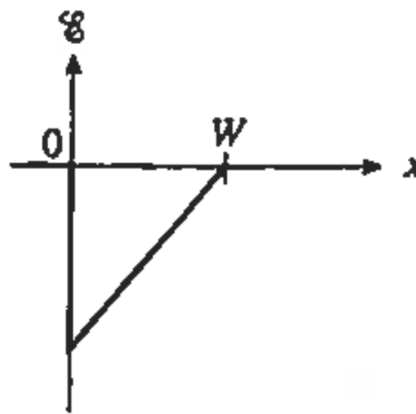
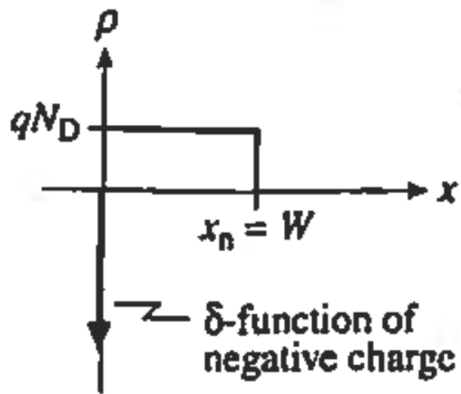


- $V_A < 0$

# Electrostatics

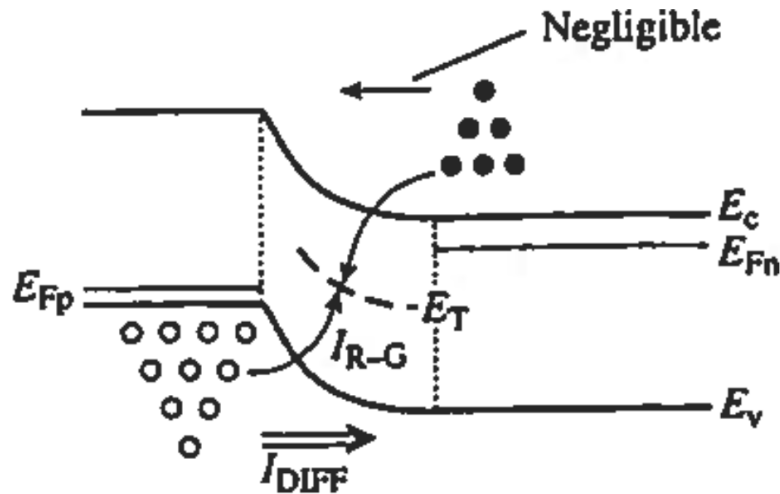


- Built-in voltage ( $V_{bi}$ )

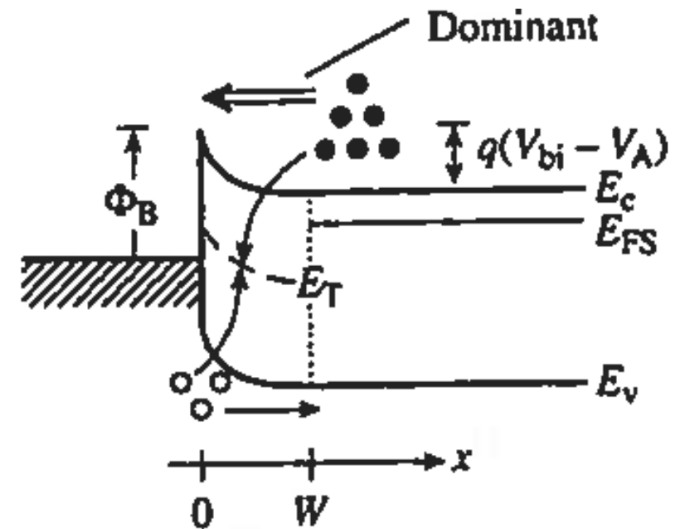


# I-V Characteristics

## Thermionic emission current



(a)  $p^+-n$  junction diode



(b) MS diode

- The electrostatics of the MS diode (Schottky diode) is similar to  $P^+N$  junction diode.
- However, mechanism of d.c. current flow (I-V) is different.
- Electron injection from the semiconductor to metal dominates in MS diode



# I-V Characteristics

- **Thermionic emission current**

- If K.E. > potential barrier
- Surmount the barrier to cross into the metal

- $K.E. = \frac{1}{2} m_n^* v_x^2 \geq q(V_{bi} - V_A)$

- $v_x \geq \sqrt{2q(V_{bi} - V_A)/m_n^*}$

- $n(v_x)$ : # of electrons having velocity of  $v_x$

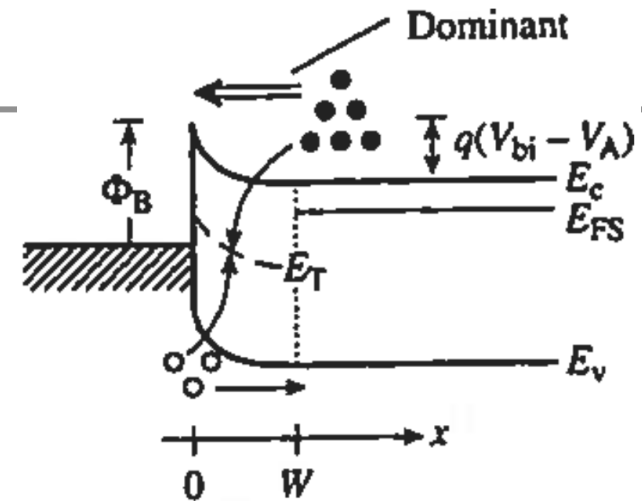
- **Drift current for the electrons having velocity of  $v_x$**

- $I_{S \rightarrow M} = -qA v_x n(v_x)$

- **Total drift current for all the electrons having velocity  $\geq v_x$**

- $I_{S \rightarrow M} = -qA \int_{-\infty}^{-v_x} v_x n(v_x) dv_x$

- $I_{S \rightarrow M} = A \left( \frac{4\pi q m_n^* k^2}{h^3} \right) T^2 e^{-\frac{\phi_B}{kT}} e^{\frac{qV_A}{kT}} = I_S e^{\frac{qV_A}{kT}}$



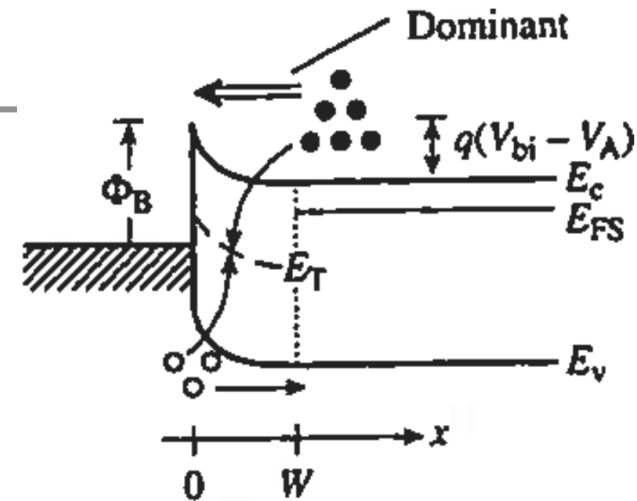
$n(v_x) \sim \text{exponential}$

# I-V Characteristics

- **Metal to semiconductor**

- Always see the same barrier ( $\phi_B$ )
- $I_{M \rightarrow S}(V_A) = I_{M \rightarrow S}(V_A = 0)$
- Under equilibrium, no net current

- $I_{M \rightarrow S}(V_A = 0) = -I_{S \rightarrow M}(V_A = 0) = -A \left( \frac{4\pi q m_n^* k^2}{h^3} \right) T^2 e^{-\frac{\phi_B}{kT}} = -I_S$



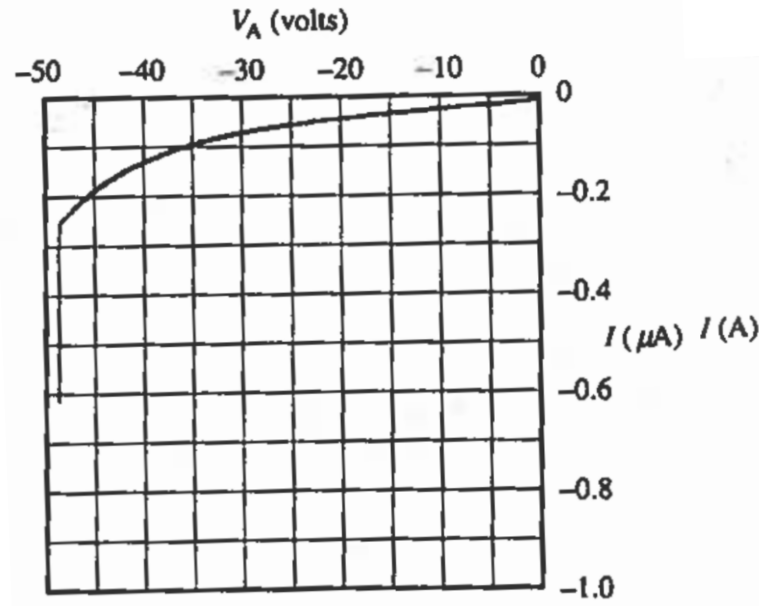
- **Total current**

- $I_{M \rightarrow S}(V_A) + I_{S \rightarrow M}(V_A)$

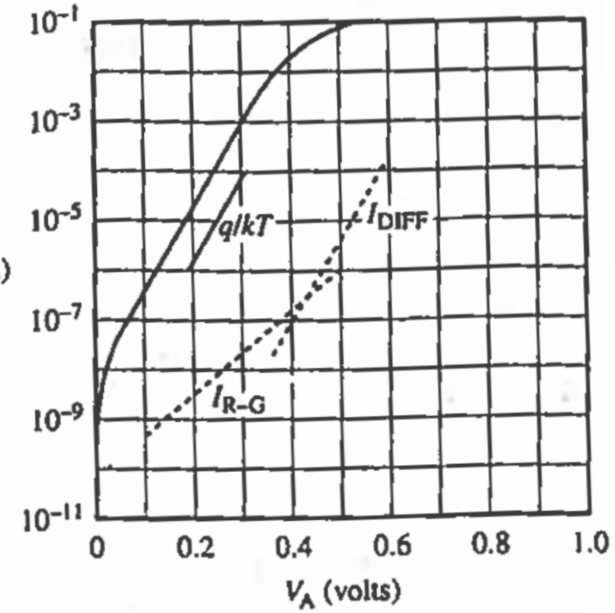
*Ideal MS diode equation...*

- $I_S \left( e^{\frac{qV_A}{kT}} - 1 \right)$

# I-V Characteristics



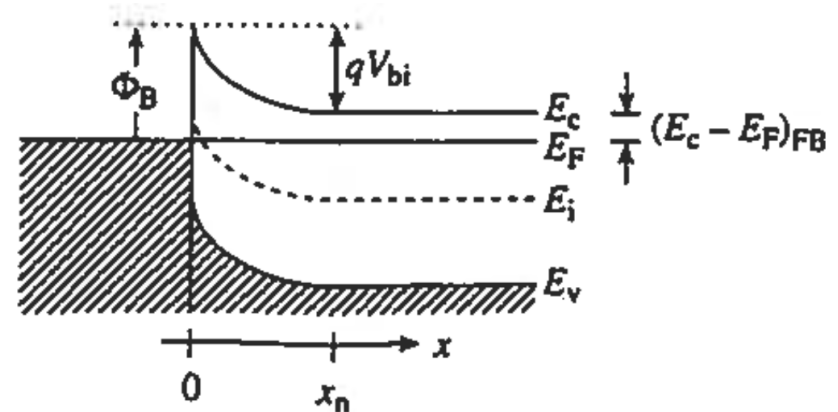
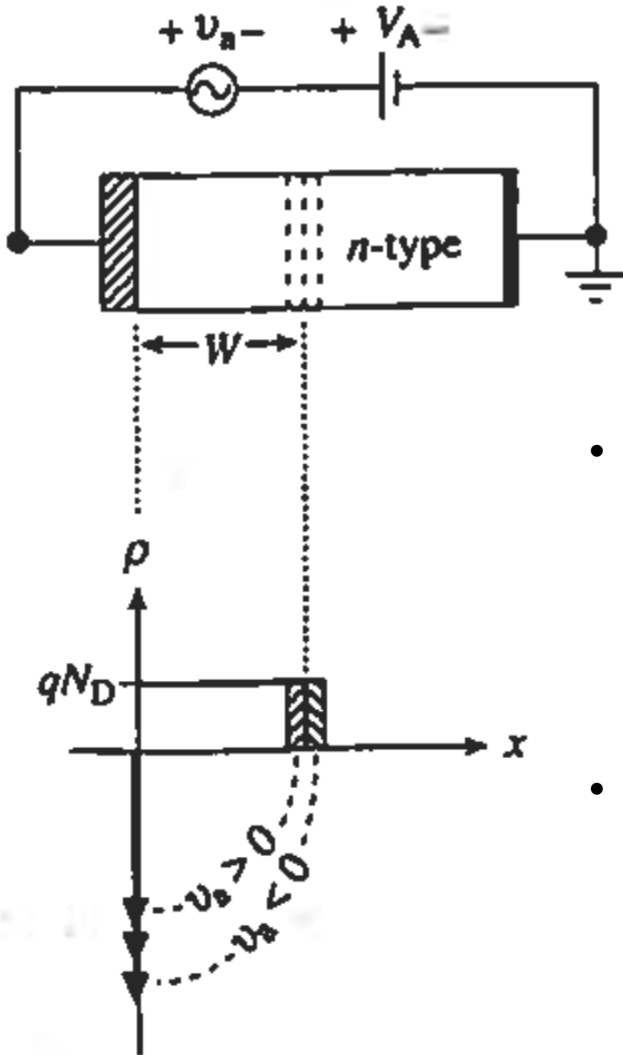
**Reverse bias**



**Forward bias**

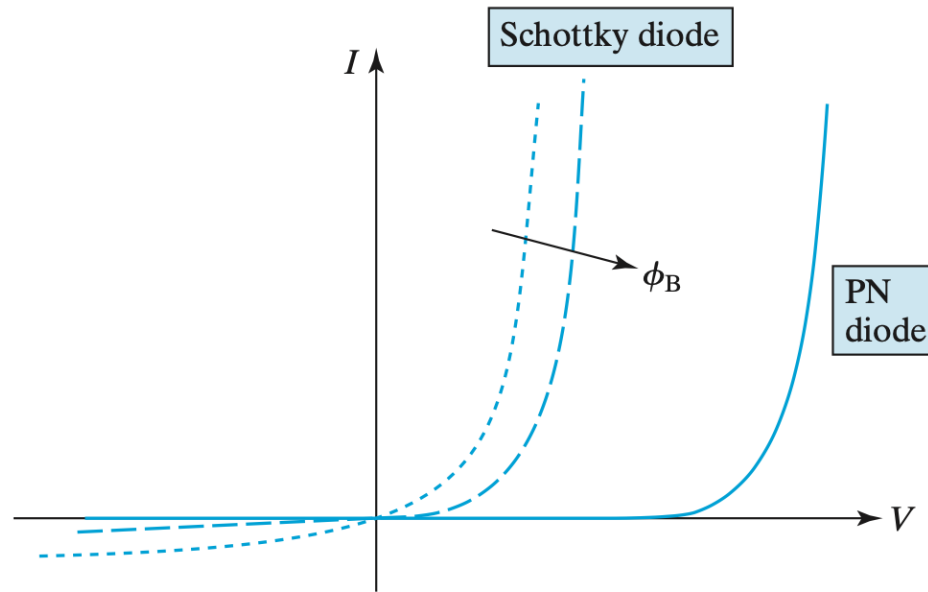
- **Non-ideal behaviors**
  - **Avalanching breakdown**
  - **Series resistance**
  - **No high level injection**
  - **Schottky barrier lowering ( $\Delta\phi_B$ )**

# a.c. Response



- **Parallel plate capacitor-like junction capacitor**
  - Different responding charges in metal
  - PN diode:
  - MS diode:
  - Majority carriers  $\rightarrow$  quick response
- **Forward bias diffusion capacitance?**
  - Diffused minority carriers are ignorable in MS diode

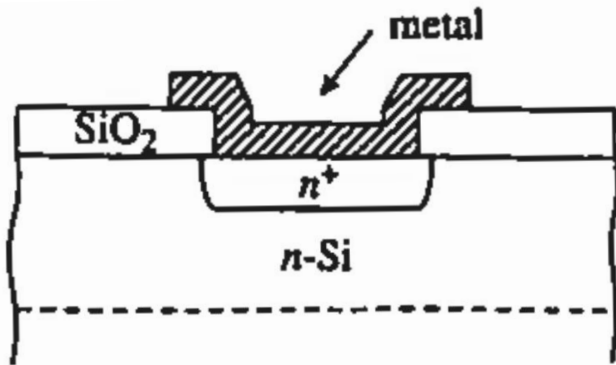
# Applications



**FIGURE 4–40** Schematic  $IV$  characteristics of PN and Schottky diodes having the same area.

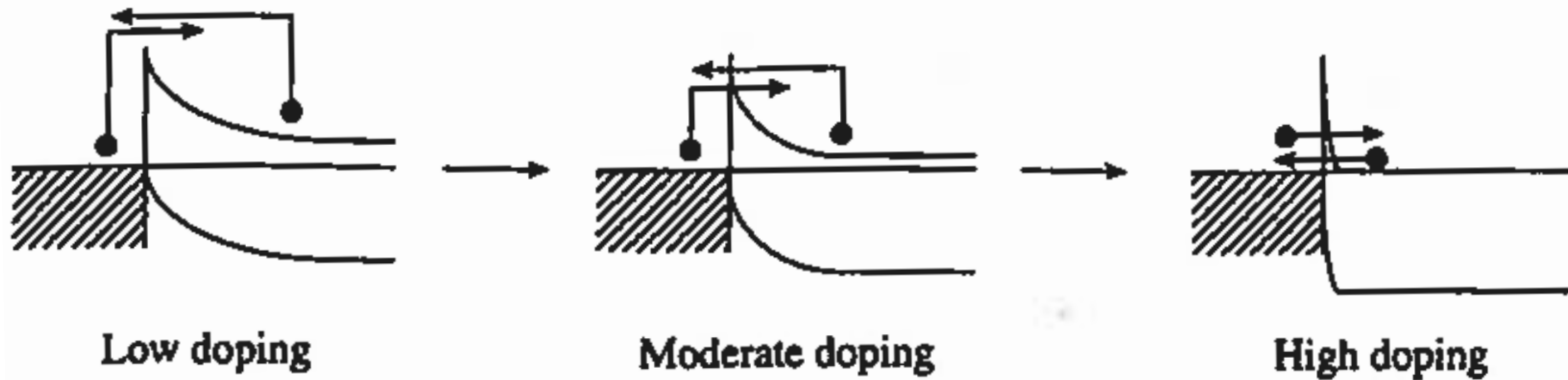
- **Low-voltage and high-current rectifier applications**
  - Smaller power loss
- **Higher speed switching applications**
  - Majority carrier driven

# Ohmic Contacts



**Table 14.1** Electrical Nature of Ideal MS Contacts.

	<i>n-type Semiconductor</i>	<i>p-type Semiconductor</i>
$\Phi_M > \Phi_S$	Rectifying	Ohmic
$\Phi_M < \Phi_S$	Ohmic	Rectifying



- In practice, it is difficult to tune the barrier height ( $\phi_B$ ).
- High doping in the semi can lead to ohmic contact regardless of  $\phi_B$ .

# Summary

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- **Metal–Semiconductor contacts**
  - Mostly depends on material characteristics
  - Could be rectifying (diode-like behavior) or ohmic (low-resistance)
  
- **Schottky Diodes (MS diode)**
  - Similar to PN diode in  $I$ – $V$  characteristics
  - Different mechanism, though.
  - Entirely majority carrier driven
    - Faster switching